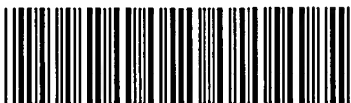


**Search Notes**

Application/Control No.

10/623,226

Examiner

Shun Lee

Applicant(s)/Patent under  
Reexamination

CHAI ET AL.

Art Unit

2878

**SEARCHED**

Class	Subclass	Date	Examiner
250	361R	2/17/2005	SL
252	301.4F	2/17/2005	SL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
As above with PGPub		2/17/2005	SL

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR